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(71) Applicant: **LECROY CORPORATION** [US/US]; 700 Chestnut Ridge Road, Chestnut Ridge, NY 10977-6499 (US).

(72) Inventors: **SALANT, Lawrence, Steven**; 5 David Drive, New Hempstead, NY 10977 (US). **GAMPER, Roland**; rue de la Prulay 27, CH-1217 Meyrin (CH).

(74) Agent: **FROMMER, William, S.**; Frommer Lawrence & Haug LLP 745 Fifth Avenue, New York, NY 10151 (US).

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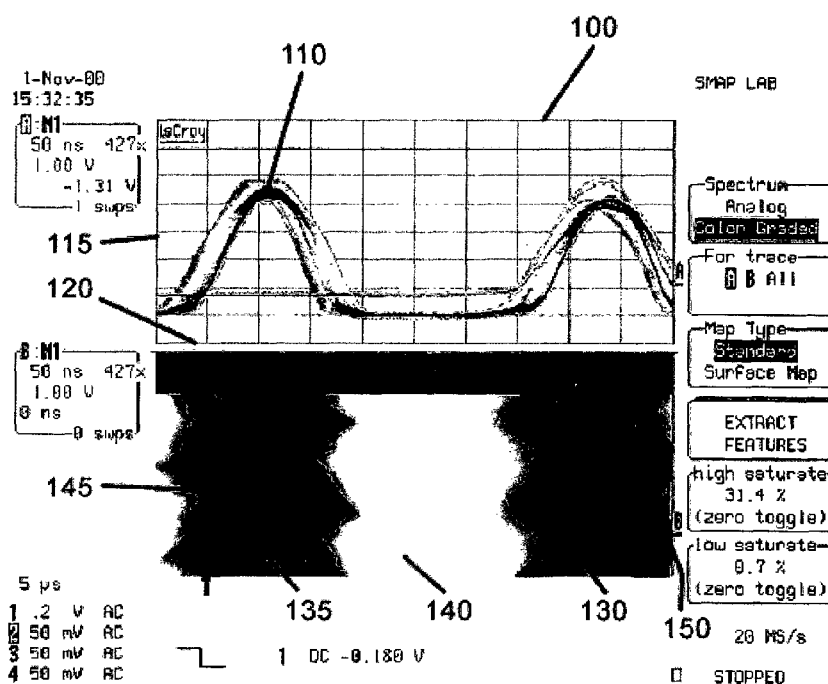
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(54) Title: SURFACE MAPPING AND 3-D PARAMETRIC ANALYSIS



(57) Abstract: A display for displaying acquired waveforms (110) from an oscilloscope. An x-axis measurement (120) designating time during an acquisition trace, a y-axis measurement (150) designating one or more acquisition traces, and a z-axis measurement (145) designating an amplitude of at least one point of one or more of the acquisition traces are provided. The z-axis (145) is indicated by a color difference, thereby displaying a surface map (135).



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